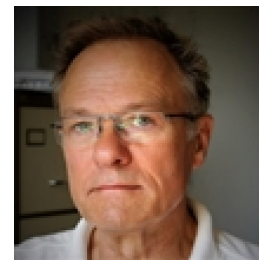


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Sven Tougaard earned the MS (1975) at the Technical University, Copenhagen, Denmark, and the PhD (1979) and dr. scient (1988) degrees in theoretical and experimental surface physics at Odense University, Denmark. He was post. doc. in USA and Germany (1978-84) and professor at the University of Southern Denmark since 1984. He founded the software company QUASES-Tougaard Inc. (1994) (www.quases.com) which develops software for characterization of the composition and electronic properties of surface nanostructures by X-ray photoelectron spectroscopy (XPS) and reflection electron energy loss spectroscopy (REELS). Prof. Tougaard received the Fyns Stitstidendes Research Prize in 1987, the Rivière Prize awarded by the UK Surface Analysis Forum in 2007, "for work which has been judged outstanding in its continuing and lasting contribution to surface analysis", and the Albert Nerken Award by the American Vacuum Society in 2012 "for contributions to the development of improved methods to characterize thin-film nanostructures by X-ray photoelectron spectroscopy". His current research focuses on experimental and theoretical studies of phenomena induced by the electron-solid interaction at surfaces and in nanostructures and development of theory for practical experimental methods to determine the chemical composition and electronic properties of nanostructures by electron spectroscopy. He has conducted and participated in several EU supported international projects on these subjects, published more than 200 scientific papers that are cited more than 7000 times with an H-index = 42 and presented more than 60 invited talks at international conferences and workshops. He has a long-standing active scientific collaboration with several research institutes in Europe, USA, Korea and Japan. He is on the Steering Committee for ECASIA (European Conf. for Surface and Interface Analysis) (2002-) and has served on the program committees and advisory boards for more than 25 international conferences and workshops. He serves on the editorial board for the journals: J. Electron Spectroscopy (1990-2012), Surface and Interface Anal. (1989-), J. of Surface Analysis (1994-), and Surface Science Spectra (1991-).

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Sato, M., Tsukamoto, N., Shiratori, T., Furusawa, T., Suzuki, N. & Tougaard, S., 2006, In: Surface and Interface Analysis. 38, p. 604-609

Quantitative analysis of reflection electron energy loss spectra for ultra-thin HfO₂, Al₂O₃ and Hf-Al-O dielectric films on Si(100)

Jin, H., Oh, S. K., Kang, H. J. & Tougaard, S., 2006, In: Journal of Applied Physics. 100, p. 083713

Tests of algorithms for angle-resolved XPS

Tougaard, S., 2006, *Annual Report March 2006, Versailles Project on Advanced Materials and Standards Technical Working Area 2: Surface Chemical Analysis*. Powell, C. J. & Seah, M. P. (eds.). p. 13-16

Theoretical Determination of the Surface Excitation Parameter from X-ray Photoelectron Spectroscopy

Pauli, N., Tougaard, S. & Yubero, F., 2006, In: *Surface and Interface Analysis*. 38, p. 672-675

What nano-physical properties can be determined by analysis of elastic peak accompanied by its inelastic background tail in XPS and AES spectra?

Hajati, S. & Tougaard, S., 2006, In: *Journal of Surface Analysis*. 13, p. 148- 155

XPS imaging of depth profiles and amount of substance based on Tougaard's algorithm

Hajati, S., Coultas, S., Blomfield, C. & Tougaard, S., 2006, In: *Surface Science*. p. 3015-3021

Algorithm for Automatic XPS Data Processing and XPS-Imaging

Tougaard, S., 2005, In: *Journal of Vacuum Science & Technology. A. Vacuum, Surfaces, and Films*. A 23, p. 741-745

Electron backscattering from surfaces: Azimuth-resolved distributions

Glazov, L. & Tougaard, S., 2005, In: *Physical Review B*. 72, 085406.

Quantification of plasmon excitations in core-level photoemission

Yubero, F. & Tougaard, S., 2005, In: *Physical Review B*. 71, p. 045414

Test of Dielectric Response Model for Energy and Angular Dependence of Plasmon Excitations in Core Level Photoemission

Yubero, F., Kover, L., Drube, W., Eickhoff, T. & Tougaard, S., 2005, In: *Surface Science*. 592, p. 1-7

Theoretical Study of the Surface Excitation Parameter from Reflection-Electron-Energy-Loss-Spectra

Pauli, N., Tougaard, S. & Yubero, F., 2005, In: *Surface and Interface Analysis*. 37, p. 1151-1157

Contribution of intrinsic and extrinsic excitations to KLL Auger spectra induced from Ge films.

Berényi, Z., Kövér, L., Tougaard, S., Yubero, F., Tóth, J. & Cserny, I., 2004, In: *Journal of Electron Spectroscopy and Related Phenomena*. 135, p. 177-182

Pulsed laser deposition of aluminum-doped ZnO films at 355 nm.

Holmelund, E., Schou, J., Thestrup, B., Tougaard, S., Johnson, E. & Nielsen, M. M., 2004, In: *Applied Physics A*. A79, p. 1137-1139

QUEELS Software Package for Calculation of Surface Effects in Electron Spectra.

Tougaard, S. & Yubero, F., 2004, In: *Surface and Interface Analysis*. 36, p. 824-827

Surface Analysis: (b) X-ray Photoelectron Spectroscopy.

Tougaard, S., 2004, *Encyclopedia of Analytical Science*. Worsfold, P., Townshend, A. & Pool, C. (eds.). 2nd Edition ed. Oxford: Academic Press, p. 445-456

Surface Roughness and Island Formation effects in ARXPS quantification.

Martin-Concepción, A. I., Yubero, F., Espinos, J. P., Garcia, J. & Tougaard, S., 2004, In: *Surface and Interface Analysis*. 36, p. 788-792

The Use of QUASESTM/XPS Measurements to Determine the Oxide Composition and Thickness on an Iron Substrate

Grosvenor, A. P., Kobe, B. A., McIntyre, N. S., Tougaard, S. & Lennard, W. N., 2004, In: *Surface and Interface Analysis*. 36, p. 632-639

Determination of amount of substance on the nanometer range consistency between XPS, RBS and XRF quantification
Martin-Concepción, A. I., Yubero, F., Espinos, J. P., Garcia, J. & Tougaard, S., 2003, In: Surface and Interface Analysis. 35, p. 984-90

Electron Backscattering from Surfaces; Invariant Embedding Approach
Glazov, L. G. & Tougaard, S., 2003, In: Physical Review B. 68, p. 155409

Experimental determination of inelastic scattering cross-sections of Si, Ge and III-V semiconductors 2003
Orosz, G. T., Gergely, G., Gurban, S., Menyhard, M., Toth, J., Varga, D. & Tougaard, S., 2003, In: Vacuum. 71, p. 147-152

Quantification of Nano-structures by Electron Spectroscopy
Tougaard, S., 2003, *Surface Analysis by Auger and X-Ray Photoelectron Spectroscopy*. Briggs, D. & Grant, J. T. (eds.). IM Publications, p. kap. 12: 295-345

Quantitative XPS: Simple algorithm to determine the amount of atoms in the outermost few nano-meters
Tougaard, S., 2003, In: Journal of Vacuum Science & Technology. A: International Journal Devoted to Vacuum, Surfaces, and Films. A21, p. 1081-86

XPS Study of First Stages of ZnO Growth and Nano-structure Dependence of the Polarization Effects at ZnO/SiO₂ and ZnO/Al₂O₃ Interfaces
Martin-Concepción, A. I., Yubero, F., Espinós, J. P., González-Elipé, A. R. & Tougaard, S., 2003, In: Journal of Vacuum Science & Technology. A: International Journal Devoted to Vacuum, Surfaces, and Films. A21, p. 1393-98

Surface morphology of SiO₂ on a Si(111) 7×7 surface formed after alternating exposure to caesium and oxygen and subsequent annealing
Semak, B. S., Jensen, T., Takker, L. B., Morgen, P. & Tougaard, S., 1. Feb 2002, In: Surface Science. 498, 1-2, p. 11-20
10 p.

Comparison of source functions obtained by using QUASES and the Partial Intensity Analyses for inelastic background correction: KLL Auger spectra of 3d transition elements Cu and Ni
Köver, L., Tougaard, S., Werner, W. S. M. & Cserny, I., 2002, In: Surface and Interface Analysis. 33, 8, p. 681-686

Comparison of the Tougaard, ARXPS, RBS and Ellipsometry methods to determine the thickness of thin SiO₂ layers
Semak, B. S., Marel, C. V. D. & Tougaard, S., 2002, In: Surface and Interface Analysis. 33, p. 238-44

Deposition and characterization of ITO films produced by laser ablation at 355 nm
Holmelund, E., Thestrup, B., Schou, J., Larsen, N. B., Nielsen, M. M., Johnson, E. & Tougaard, S., 2002, In: Applied Physics A. p. A74; 147-52

Determination of Inelastic Mean Free Path of High Energy Electrons from Shape Analysis of K- Auger and K- conversion Spectra Emitted from Thin Films
Köver, L., Tougaard, S., Toth, J., Varga, D., Dragoun, O., Koval'k, A. & Rysavy, M., 2002, In: Journal of Surface Analysis. 9, p. 281-4

Experimental estimation of surface excitation parameter for surface analysis
Gergerly, G., Menyhard, M., Gurban, S., Sulyok, A., Toth, J., Varga, D. & Tougaard, S., 2002, In: Surface and Interface Analysis. p. 33; 410-3

Pure and Sn-doped ZnO films produced by pulsed laser deposition
Holmelund, E., Schou, J., Tougaard, S. & Larsen, N. B., 2002, In: Applied Surface Science. p. 197-198; 467-71

Recent progress in silicon oxidation: Towards ultra thin oxides

Morgen, P., K.-Dam, F., Gundlach, C., Jensen, T., Tækker, L.-B., Tougaard, S. & Pedersen, K., 2002, In: Recent Res Devel Appl Phys. 5, p. 287-311

Surface Morphology of SiO₂ grown on a Si(111)7x7 surface by alternating exposure to Caesium and Oxygen and Subsequent Annealing

Semak, B. S., Jensen, T., Tækker, L. B., Morgen, P. & Tougaard, S., 2002, In: Surface Science. p. 498; 11-20.

Determination of overlayer thickness by QUASES analysis of photon excited KLL Auger spectra of Ni and Cu films

Kövéér, L., Tougaard, S., Tóth, J., Daróczy, L., Szabó, I., Langer, G. & Menyhárd, M., 2001, In: Surface and Interface Analysis. 31, p. 271B9

Intercomparison of Methods for Separation of REELS Elastic Peak Intensities for Determination of IMFP

Tougaard, S., Krawczyk, M., Jablonski, A., Pavluch, J., Tóth, J., Varga, D., Gergely, G., Menyhárd, M. & Sulyok, A., 2001, In: Surface and Interface Analysis. 31, p. 1-10

Practical Correction Procedures for Elastic Electron Scattering Effects in ARXPS

Lassen, T. S., Tougaard, S. & Jablonski, A., 2001, In: Surface Science. 481, p. 150-62

Probing the ex situ morphology of Ge islands on Si(001): AFM and XPS inelastic peak shape analysis

Simonsen, A. C., Tougaard, S., Lundsgaard Hansen, J. & Nylandsted Larsen, A., 2001, In: Surface and Interface Analysis. 31, 4, p. 328-337 10 p.

Quantification of Well-characterized Langmuir-Blodgett Film by Analysis of the PeakShape of XPS taken at Different Emission Angles.

Suzuki, N., Kato, T. & Tougaard, S., 2001, In: Surface and Interface Analysis. 31, p. 862-8

Surface Excitation Effects in Electron Spectroscopy

Gergely, G., Menyhárd, M., Gurban, S., Sulyok, A., Tóth, J., Varga, D. & Tougaard, S., 2001, In: Solid State Ionics. 141-142, p. 47-51

Surface Morphology of PS-PDMS Diblock Copolymer Films

Andersen, T. H., Tougaard, S., Larsen, N. B., Amdal, K. & Johannsen, I., 2001, In: Journal of Electron Spectroscopy and Related Phenomena. 121, p. 93-110

Analysis of angle-resolved electron energy loss in XPS spectra of Ag, Au, Co, Cu, Fe and Si

Simonsen, A. C., Youbero, F. & Tougaard, S., 1999, In: Surface Science. 436, 1, p. 149-159

Escape Probability of Electrons from Solids. Influence of Elastic Electron Scattering

Jablonski, A. & Tougaard, S., 1999, In: Surface Science. 432, p. 211-27

Nanostructure of Ge deposited on Si(001): a study by XPS peak shape analysis and AFM

Simonsen, A. C., Schleberger, M., Tougaard, S., Lundsgaard Hansen, J. & Nylandsted Larsen, A., 1999, In: Thin Solid Films. 338, 1-2, p. 165-71 7 p.

Quantification of Au deposited on Ni: XPS peak shape analysis compared to RBS

Simonsen, A. C., Pøhler, J. P., Jeynes, C. & Tougaard, S., 1999, In: Surface and Interface Analysis. 27, 1, p. 52-56 5 p.

Ge growth on Si(001) studied by x-ray photoelectron spectroscopy peakshape analysis and atomic force microscopy

Schleberger, M., Simonsen, A. C., Tougaard, S., Lundsgaard Hansen, J. & Nylandsted Larsen, A., 1. Nov 1997, In: Journal of Vacuum Science & Technology. A. Vacuum, Surfaces, and Films. 15, 6, p. 3032-3035 4 p.

Quantitative model of electron energy loss in XPS

Simonsen, A. C., Yubero, F. & Tougaard, S., 15. Jul 1997, In: Physical Review B. 56, 3, p. 1612-1619 8 p.

Quantitative XPS: non-destructive analysis of surface nano-structures

Tougaard, S. M., Jul 1996, In: Applied Surface Science. 100-101, p. 1-10

Deconvolution of inelastic background signal from XPS spectra of homogeneous solids

Tougaard, S. M. & Jørgensen, B., 1987, In: Surface Science. 182, 3, p. L253-L256

Elastic and inelastic scattering of electrons emitted from solids: effects on energy spectra and depth profiling in xps/aes

Tofterup, A. L., Tougaard, S. & Sigmund, P., Jul 1986, In: Surface and Interface Analysis. 9, 2, p. 130

Quantitative non-destructive in-depth composition information from XPS

Tougaard, S. M., 1986, In: Surface and Interface Analysis. 8, 6, p. 257-260

Influence of elastic and inelastic scattering on energy spectra of electrons emitted from solids

Tougaard, S. & Sigmund, P., 1982, In: Physical Review B. 27, 7, 4452.

Mechanisms for oxygen adsorption on the Si(110) surface studied by Auger electron spectroscopy

Tougaard, S., Morgen, P. & Onsgaard, J., 2. Nov 1981, In: Surface Science. 111, 3, p. 545-554 10 p.

Electron Emission from Solids During Ion Bombardment: Theoretical Aspects

Sigmund, P. & Tougaard, S. M., 1981, *Inelastic Particle-Surface Collisions: Proceedings of the Third International Workshop on Inelastic Ion-Surface Collisions Feldkirchen-Westerham, Fed. Rep. of Germany September 17-19, 1980*. Taglauer, E. & Heiland, W. (eds.). Berlin: Springer, p. 2-37 (Springer Series in Chemical Physics, Vol. 17).

ADSORPTION OF N₂ ON W(100) UNDER LONG EXPOSURE.

Winters, H. F., Morgen, P., Tougaard, S. & Onsgaard, J., 1. Jan 1980, p. 303-306. 4 p.

Scandium and lutetium surfaces studied by reflection electron energy-loss spectroscopy

Onsgaard, J., Tougaard, S., Morgen, P. & Ryborg, F., 1. Jan 1980, In: Journal of Electron Spectroscopy and Related Phenomena. 18, 1, p. 29-41 13 p.

SCANDIUM, YTTRIUM AND LUTETIUM SURFACES STUDIED BY ELECTRON SPECTROSCOPY.

Onsgaard, J., Tougaard, S., Morgen, P. & Ryborg, F., 1. Jan 1980, p. 1361-1364. 4 p.

Observation of changes in the electronic density of states at a Si (111) surface during adsorption of oxygen by Auger electron spectroscopy

Morgen, P., Onsgaard, J. H. & Tougaard, S., 1. Dec 1979, In: Applied Physics Letters. 34, 8, p. 488-490 3 p.

Segregation of impurities at the surface of a scandium single crystal

Onsgaard, J., Tougaard, S. & Morgen, P., 1. Jan 1979, In: Applications of Surface Science. 3, 1, p. 113-117

Desorption from powdered ZnO during electron bombardment and interaction with atomic hydrogen

Morgen, P., Onsgaard, J. H. & Tougaard, S., 1. Dec 1977, In: Journal of Applied Physics. 48, 8, p. 3443-3447 5 p.

Conductivity of powdered ZnO with chemisorbed oxygen during photodesorption

Morgen, P., Onsgaard, J. H. & Tougaard, S., 1. Dec 1976, In: Journal of Applied Physics. 47, 11, p. 5094-5096 3 p.

Activities

32nd European Conference On Surface Science (ECOSS-32)

Tougaard, S. M. (Organizer)
28. Aug 2016 → 2. Sept 2016

6th International Conference on Theoretical and Applied Physics (6th ICTAP)

Tougaard, S. M. (Organizer)

19. Sept 2016 → 21. Sept 2016

6th International Symposium on Flexible Organic Electronics

Tougaard, S. M. (Participant)

7. Jul 2013 → 11. Jul 2013

7th International Symposium on Practical Surface Analysis (PSA-16)

Tougaard, S. M. (Organizer)

16. Oct 2016 → 21. Oct 2016

8th International Symposium on Practical Surface Analysis (PSA-19),

Tougaard, S. M. (Program committee member)

Nov 2019

American Vacuum Society 59th annual meeting

Tougaard, S. M. (Participant)

2012

Analytical and Bioanalytical Chemistry (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Analytical Sciences (Journal)

Tougaard, S. M. (Peer reviewer)

2010

A Near Real-time Data Analysis Package to Enhance the Information Extracted from XPS Spectra

Tougaard, S. M. (Other)

25. Aug 2010

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

2012

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

3. May 2016

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

29. May 2016

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

8. Mar 2018

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

1. Oct 2018

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)
11. Oct 2021

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)
28. Feb 2022

Applied Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)
2. Jun 2022

Arranged a Tutorial at Lokey Laboratories, University of Oregon: Using QUASES for Quantitative XPS and Auger Analysis of Surface Nanostructures

Tougaard, S. M. (Other)
28. Apr 2009

Automated XPS analysis and XPS-Imaging of nano-structures

Tougaard, S. M. (Lecturer)
13. Oct 2010 → ...

Bedømmelsesudvalg for "Fonds de la Recherche Scientifique - FNRS", Belgium. (External organisation)

Tougaard, S. M. (Member)
1. Feb 2009 → 12. Feb 2009

Bedømmelsesudvalg for "Fonds de la Recherche Scientifique - FNRS", Belgium. (External organisation)

Tougaard, S. M. (Member)
31. Mar 2010 → 15. Apr 2010

Censor i Faststoffysik på Aarhus Universitet

Tougaard, S. M. (Censor)
14. Jan 2015 → 16. Jan 2015

Censor i Faststoffysik på Aarhus Universitet

Tougaard, S. M. (Censor)
23. Mar 2015

Characterization of morphology of nano-structures by XPS

Tougaard, S. M. (Lecturer)
2. Apr 2014

Characterization of morphology of nano-structures by XPS

Tougaard, S. M. (Lecturer)
8. Apr 2014

Characterization of nano-structured materials with XPS-peak shape analysis

Tougaard, S. M. (Lecturer)
17. Aug 2010 → ...

Characterization of nano-structured materials with XPS-peak shape analysis

Tougaard, S. M. (Lecturer)
20. Aug 2010

Charles University

Tougaard, S. M. (Visiting researcher)

11. Nov 2009 → 13. Nov 2009

Combining high-resolution core-level and inelastic background analysis in HAXPES to investigate deeply buried interfaces

Tougaard, S. M. (Lecturer)

2. Oct 2015

Course: QUASES Analysis

Tougaard, S. M. (Guest lecturer)

25. Sept 2018

Czech Academy of Sciences

Tougaard, S. M. (Visiting researcher)

10. Nov 2009

Danmarks Tekniske Universitet (External organisation)

Tougaard, S. M. (Member)

19. Dec 2014

ECASIA-13

Tougaard, S. M. (Organizer)

19. Oct 2013

ECASIA-15 European Conference on Applications of Surface and Interface Analysis

Tougaard, S. M. (Organizer)

27. Sept 2015 → 2. Oct 2015

ECASIA 19

Tougaard, S. M. (Program committee member)

Sept 2019

ECASIA 24: Invited talk: "Recent advances in XPS, NAP-XPS, and HAXPES to Characterize Nano-Structured Materials "

Tougaard, S. M. (Guest lecturer)

14. Jun 2024

Ecole Thematique: "Workshop on XPS analysis"

Tougaard, S. M. (Organizer)

27. Sept 2016 → 28. Sept 2016

Invited talk at UKSAF meeting in Newcastle: "Quantitative XPS of surface nano-structures by analysis of the peak shape"

Tougaard, S. M. (Lecturer)

9. Jan 2007

Invited Talk held at Univ of Newcastle: "Characterization of morphology and electronic properties of surface nano-structures by photo- and reflection electron spectroscopy"

Tougaard, S. M. (Lecturer)

10. Jan 2007

European Conference on Surface Science (ECOSS)

Tougaard, S. M. (Organizer)

30. Aug 2014 → 5. Sept 2014

European Synchrotron Radiation Facility

Tougaard, S. M. (Visiting researcher)

10. Jul 2015 → 14. Jul 2015

External examiner on PhD thesis at Tampere University of Technology, Finland: "Oxidation Induced Nanostructures on Copper Alloy and Austenitic Steel Surfaces Studied by Electron Spectroscopic Methods"

Tougaard, S. M. (Censor)

4. Oct 2007

External examiner on PhD thesis at Helsinki University of Technology: "Development of XPS Data Analysis and its Application to Gas Sensor and Catalyst Surface Studies."

Tougaard, S. M. (Censor)

14. Aug 2007

Extrinsic and intrinsic effects in XPS: Validity of the two-step model and corrections for surface and core-hole effects

Tougaard, S. M. (Lecturer)

3. Aug 2011

Extrinsic and Intrinsic Effects in XPS: Validity of the two-step model and corrections for surface and core-hole effects

Tougaard, S. M. (Lecturer)

13. Oct 2010 → ...

Founder and director of the software company: "QUASES-Tougaard ApS" (External organisation)

Tougaard, S. M. (Member)

20. Feb 1994 → ...

Gave a course for Industry and PhD students from USA, UK and central Europe

Tougaard, S. M. (Guest lecturer)

22. Mar 2017

Gave a course for Industry and PhD students held at University of Surrey, UK: "SURFACE ANALYSIS: AN INTRODUCTION TO XPS, SCANNING AUGER MICROSCOPY AND SECONDARY ION MASS SPECTROMETRY": PhD kursus

Tougaard, S. M. (Guest lecturer)

23. Apr 2007 → 27. Apr 2007

Gave a course for Industry and PhD students held at University of Surrey, UK: "Surface Analysis: XPS, Auger and SIMS": PhD kursus

Tougaard, S. M. (Lecturer)

18. Mar 2013 → 22. Mar 2013

Gave a course for Industry and PhD students held at University of Surrey, UK: "Surface Analysis: XPS, Auger and SIMS": Quantitative Analysis of Surfaces by Electron Spectroscopy' and software tutorial on applications of Quases-Tougaard software packages

Tougaard, S. M. (Lecturer)

24. Mar 2015 → 25. Mar 2015

Gave a one day course on quantitative XPS of nano-structured materials

Tougaard, S. M. (Guest lecturer)

6. Jul 2017

Gave a workshop: XPS analysis using the QUASES-Tougaard software packages at the ECASIA conference

Tougaard, S. M. (Guest lecturer)

27. Sept 2015

> Industrial Application Division

Tougaard, S. M. (Visiting researcher)

20. Jan 2013 → 23. Jan 2013

Hasanuddin University

Tougaard, S. M. (Visiting researcher)
30. Mar 2014 → 5. Apr 2014

ICPPC-2010 International Conference on Polymer Processing and Characterization

Tougaard, S. M. (Participant)
15. Jan 2010 → 19. Jan 2010

Imperial College Press, London: Electron Elastic Scattering and Inelastic Scattering in Surface Electron Spectroscopy (Journal)

Tougaard, S. M. (Peer reviewer)
4. Oct 2011

Institute Of Physics IOP Nanotechnology (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

International Congress on Materials and Renewable Energy (MRE 2013)

Tougaard, S. M. (Participant)
1. Jul 2013 → 3. Jul 2013

Intrinsic and Extrinsic Excitations in XPS (and AES): Validity of the two-step model and corrections for surface and core hole effects

Tougaard, S. M. (Lecturer)
19. Aug 2010

Invited Albert Nerken Award lecture: "Characterization of thin-film nano-structures by XPS"

Tougaard, S. M. (Lecturer)
29. Oct 2012

Invited talk: "Analytical Approach for Quantitative Surface Chemical Analysis using AES and XPS"

Tougaard, S. M. (Lecturer)
2013

Invited talk at NanoTech Insight 2007 Luxor, Egypt: "Characterization of morphology and electronic properties of surface nano-structures by photo- and reflection electron spectroscopy"

Tougaard, S. M. (Lecturer)
16. Mar 2007

Invited talk at workshop "Optimizing Information Content of X-ray Photoelectron Spectroscopy Analys" at University of Oregon, USA: "Quantitative and non-destructive in-depth analysis of surface nano-structures"

Tougaard, S. M. (Lecturer)
27. Apr 2009

Invited talk at "55th IUVESTA workshop: Electron Transport Parameters; Applications in Surface Analysis": "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Tougaard, S. M. (Lecturer)
15. Sept 2008

Invited talk: "Characterization of Nano-structures from Analysis of the XPS Background: Automation and 3D-imaging"

Tougaard, S. M. (Lecturer)
29. Oct 2011 → 5. Nov 2011

Invited talk: "Nano-structure Information from XPS; Automated data analysis and 3D-imaging"

Tougaard, S. M. (Lecturer)

4. Oct 2010

Invited talk: "Nano-Structure Information from XPS; Automated Data Analysis and 3D-Imaging"

Tougaard, S. M. (Speaker)

24. Aug 2010

Invited talk: New developments (since last PSA 16) in Practical Applications of Inelastic Background Analysis to Characterize nano-structures

Tougaard, S. M. (Guest lecturer)

5. Nov 2019

INVITED TALK Novel Applications of Inelastic Background Analysis: HAXPES and 3D Imaging

Tougaard, S. M. (Guest lecturer)

24. Sept 2018

Invited talk: Novel Applications of XPS-Inelastic Background Analysis: 3D imaging and HAXPES

Tougaard, S. M. (Guest lecturer)

17. Oct 2017

Invited talk: "Quantitative XPS: Getting the Most Out of Your Instrument"

Tougaard, S. M. (Guest lecturer)

5. Jul 2017

Invited talk: XPS and HAXPES to Characterize Nano-Structured Materials

Tougaard, S. M. (Guest lecturer)

14. Sept 2022

Invited talk: "XPS, APXPS, and HAXPES to Characterize Nano-Structured Materials"

Tougaard, S. M. (Guest lecturer)

25. Sept 2023 → 29. Sept 2023

Invited Tutorial at workshop "Optimizing Information Content of X-ray Photoelectron Spectroscopy Analys" at University of Oregon, USA: "QUASES software applied to XPS-Nanostructure Characterization"

Tougaard, S. M. (Lecturer)

28. Apr 2009

Invited talk: "Non-Destructive Characterization of Nano-Structures by XPS"

Tougaard, S. M. (Lecturer)

2013

IVC18- International Vacuum Congress

Tougaard, S. M. (Speaker)

7. Aug 2010

J of Physics: Condensed Matter (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

J. of Physics: Condensed Matter: The validity of semi-classical approach in calculation of surface excitation parameter (Journal)

Tougaard, S. M. (Peer reviewer)

23. Jun 2011

Jopurnal Electron Spectroscopy (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Journal Electron Spectroscopy (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal Electron Spectroscopy (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Journal of Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Editor)

20. Jun 1988 → 1. Jan 2012

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Editor)

1. Jan 2010

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Peer reviewer)

8. Apr 2015

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Peer reviewer)

6. May 2015

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Peer reviewer)

9. Jun 2016

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Peer reviewer)

13. Jan 2013

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Peer reviewer)

12. May 2022

Journal of Electron Spectroscopy and Related Phenomena (Journal)

Tougaard, S. M. (Peer reviewer)

1. Jul 2022

Journal of Materials Chemistry (Journal)

Tougaard, S. M. (Editor)

1. Jan 2010

Journal of Physics D: Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Journal of Physics D: Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Journal of Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Surface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 1994 → ...

Journal of Surface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Surface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Journal of Surface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

2010

Journal of Electron Spectroscopy (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Journal Surface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

2010

Journal Vacuum Science and Technology (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

J Phys D: Applied Physics (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

J. Phys. D: Applied Phys (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

J. Phys. D: Appl. Phys (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Julius-Maximilian University of Würzburg

Tougaard, S. M. (Visiting researcher)

22. Jun 2009 → 24. Jun 2009

Julius-Maximilian University of Würzburg

Tougaard, S. M. (Visiting researcher)

6. Jun 2011 → 18. Jun 2011

Julius-Maximilian University of Würzburg

Tougaard, S. M. (Visiting researcher)

25. Jul 2011 → 6. Aug 2011

Keynote Speaker: Novel applications of inelastic background analysis: 3D imaging and HAXPES

Tougaard, S. M. (Lecturer)

17. Oct 2016

Leader of research program supported by BCR, EU (External organisation)

Tougaard, S. M. (Member)

1. Jan 1989 → 31. Dec 1994

Leader of the international research program: "Tests of Algorithms for Data Processing in XPS under Versailles Project on Advanced Materials and Standards (VAMAS)" (External organisation)

Tougaard, S. M. (Member)

1. Jan 1997 → 1. Feb 2007

Materials Science Center

Tougaard, S. M. (Visiting researcher)

20. Oct 2007 → 27. Oct 2007

Member of *Center of Excellence: "Surface Phenomena and Reactions"* (External organisation)

Tougaard, S. M. (Member)

1. Feb 2003 → 1. Feb 2007

Member of International Program Advisory Board for "International Symposium on Surface Science -Focusing on Nano-, Green, and Biotechnologies- (ISSS-6)"

Tougaard, S. M. (Organizer)

28. Jan 2010 → 15. Dec 2011

Member of Program Committee for 5th International Symposium on Practical Surface Analysis

Tougaard, S. M. (Organizer)

21. Oct 2010 → ...

Member of Program Committee for "5th International Symposium on Practical Surface Analysis (PSA-10)"

Tougaard, S. M. (Organizer)

1. Nov 2009 → 10. Oct 2010

Member of Program Committee for European Conference for Surface and Interface Analysis

Tougaard, S. M. (Organizer)

4. Sept 2011

Member of steering committee for "European conference for applications of surface and interface analysis-ECASIA 09"

Tougaard, S. M. (Organizer)

16. Oct 2009 → 23. Oct 2009

Member of the International Steering Committee for the conference: "European Conference on Applications of Surface and Interface Analysis (ECASIA-07)"

Tougaard, S. M. (Organizer)

9. Sept 2007 → 14. Sept 2007

Member of the Program Committee for "55th IUVESTA Workshop on Electron Transport Parameters Applied in Surface Analysis"

Tougaard, S. M. (Organizer)

14. Sept 2008 → 17. Sept 2008

Member of the Program Committee for "International Symposium on Practical Surface Analysis 2007", Japan

Tougaard, S. M. (Organizer)

25. Nov 2007 → 28. Nov 2007

Member of the Program Committee for "2nd International Workshop on Hard X-ray Photoelectron Spectroscopy" at SPring-8, Japan

Tougaard, S. M. (Organizer)

19. Sept 2006 → 20. Sept 2006

Member, since 2002 of the "International Steering Committee for European Conference on Applications of Surface and Interface Analysis (ECASIA)" (External organisation)

Tougaard, S. M. (Member)

20. Apr 2002 → ...

Model to correct XPS and AES for core hole-, transport- and surface effects. Validity and practical applications

Tougaard, S. M. (Lecturer)

1. Sept 2014

Nanostructures Characterized by Electron Spectroscopy.

Tougaard, S. M. (Lecturer)

15. Jun 2011

Nanotechnology (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Nanotechnology (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Nano Technology (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

National Institute for Materials Science Tsukuba

Tougaard, S. M. (Visiting researcher)

10. Oct 2010 → 13. Oct 2010

National University of Singapore (External organisation)

Tougaard, S. M. (Member)

1. Jan 2009 → 1. Mar 2009

Near real time data analysis and other approaches to enhancing information from XPS

Tougaard, S. M. (Lecturer)

21. Oct 2009

New technique for non-destructive 3D-imaging of nano-structures

Tougaard, S. M. (Lecturer)

27. Oct 2010

"Non-destructive characterization of nano-structures by analysis of the peak shape in photoelectron spectra"

Tougaard, S. M. (Lecturer)

20. Jan 2013 → 23. Jan 2013

Non-destructive imaging of nanostructures by analysis of the photoelectron peak shape

Tougaard, S. M. (Lecturer)

30. Aug 2016

Pacific Northwest National Laboratory

Tougaard, S. M. (Visiting researcher)

28. Apr 2009 → 2. May 2009

Paris Diderot University

Tougaard, S. M. (Visiting researcher)

18. May 2008 → 25. May 2008

Participated in the international reserach project: "Synchrotron Microanalysis: accurate and traceable elemental analysis on the microscopic level" (External organisation)

Tougaard, S. M. (Member)

1. Jan 2000 → 1. Jul 2005

Participated in "The Latest in XPS Technology" meeting at Risoe, Denmark

Tougaard, S. M. (Participant)

7. Jun 2007 → 8. Jun 2007

Physical Review B (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Plenary lecture: Quantitative XPS and HAXPES

Tougaard, S. M. (Guest lecturer)

5. Oct 2021

Poster at "European Conference on Surface and Interface Analysis": "Characterization of Au nano-cluster formation on and diffusion in Polystyrene using XPS peak shape analysis"

Tougaard, S. M. (Lecturer)
10. Sept 2007

Poster at "European Conference on Surface and Interface Analysis": "Test of validity of the V-type trajectory assumption in REELS experiments"

Tougaard, S. M. (Lecturer)
13. Sept 2007

Poster at "European Conference on Surface and Interface Analysis": "Theoretical determination of the surface excitation parameter for Ti, Fe, Cu, Pd, Ag, and Au"

Tougaard, S. M. (Lecturer)
12. Sept 2007

Quantitative Analysis of Surfaces by Electron Spectroscopy

Tougaard, S. M. (Lecturer)
24. Mar 2015

Quantitative Analysis of Surfaces by Electron Spectroscopy. XPS and AES

Tougaard, S. M. (Keynote speaker)
26. Sept 2016 → 30. Sept 2016

"Quantitative XPS: effects of core-hole and surface excitations"

Tougaard, S. M. (Lecturer)
26. Aug 2010

Quantitative XPS: Effects of core-hole and surface excitations

Tougaard, S. M. (Lecturer)
7. Oct 2010 → ...

Quantitative XPS of nano-structures with the Quases software-Practical applications and tutorial examples

Tougaard, S. M. (Lecturer)
19. Oct 2015 → 21. Oct 2015

QUASES workshop

Tougaard, S. M. (Guest lecturer)
27. Sept 2015

QUASES-workshop

Tougaard, S. M. (Organizer)
27. Sept 2015

QUASES-XPS analysis of surface nano-structures

Tougaard, S. M. (Guest lecturer)
16. Jun 2019 → 21. Jun 2019

QUASES XPS Master Class

Tougaard, S. M. (Guest lecturer)
25. Sept 2023

REM8-8th International Meeting on recent developments in the study of radiation effects in matter

Tougaard, S. M. (Participant)
20. Sept 2015 → 23. Sept 2015

Scientific leader of the international research program: "Determination of Standardized Parameters Describing the Electron Transport for Quantitative Surface Analysis by Electron Spectroscopies" (External organisation)

Tougaard, S. M. (Member)

1. Jan 1998 → 1. Jan 2002

Short Course at ECASIA 24: "Quantitative XPS by visual inspection of the XPS survey and by QUASES software"

Tougaard, S. M. (Guest lecturer)

9. Jun 2024

Short Course on Quases-XPS analysis of nano-structured surfaces

Tougaard, S. M. (Guest lecturer)

2. Jul 2019

Software Package to Calculate the Effects of Core hole and Surface Excitations on XPS and AES

Tougaard, S. M. (Lecturer)

6. Sept 2011

Spring-8, Japan: "Non-destructive characterization of nano-structures by analysis of the peak shape in photoelectron spectra "

Tougaard, S. M. (Lecturer)

21. Jan 2013

Invited talk at ECASIA: "Nano-Structure Information from XPS; Automatic Data Analysis and 3D-Imaging"

Tougaard, S. M. (Lecturer)

21. Oct 2009

Invited talk: "Characterization of nano-structured polymers by XPS-peak shape analysis"

Tougaard, S. M. (Lecturer)

17. Jan 2010

REELS as a quantitative method to characterize the electronic properties of surface nano-structures

Tougaard, S. M. (Lecturer)

20. Jun 2007

Surface excitation parameter: Theoretical determination and application in Monte Carlo simulations

Tougaard, S. M. (Lecturer)

22. Oct 2009

Talk at "American Vacuum Society 55th International Symposium": "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Tougaard, S. M. (Lecturer)

22. Oct 2008

Talk at "Samsung Advanced Institute of Technology" , Seoul Korea: "Algorithm for Automatic XPS Data Analysis: Quantification of Surface Nano-structures and Application to 3D-XPS Imaging"

Tougaard, S. M. (Lecturer)

10. Jan 2009

Talk at Chungbuk National University, Korea: "Algorithm for Automatic XPS Data Analysis: Quantification of Surface Nano-structures and Application to 3D-XPS Imaging"

Tougaard, S. M. (Lecturer)

19. Mar 2008

Invited talk at "Practical Surface Analysis 07" in Kanazawa Japan: "Algorithm for Automatic XPS Data Analysis: Quantification of Surface Nano-structures and Application to 3D-XPS Imaging"

Tougaard, S. M. (Lecturer)
28. Nov 2007

Surface Analysis 2009; 31st AVS-Symposium on Applied Surface Analysis

Tougaard, S. M. (Participant)
22. Apr 2009 → 24. Apr 2009

Surface Analysis Course at Univ. of Surrey, UK

Tougaard, S. M. (Speaker)
2013

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 1987 → ...

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)
1. Jan 2008

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Editor)

1. Jan 2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

7. Sept 2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

1. Nov 2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

2010

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

12. Jan 2011

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

2011

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

2011

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

27. Feb 2012

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

2012 → ...

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
2012 → ...

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
2012 → ...

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
Sept 2013

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
Oct 2013

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
12. Nov 2013

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
18. Nov 2013

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
Feb 2014

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
21. Feb 2014

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
May 2015

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
14. Aug 2015

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
19. Sept 2015 → ...

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
30. Oct 2015

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)
20. May 2016

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

25. Jun 2016

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

15. Jul 2016

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

13. Sept 2018

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

Oct 2018

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

1. Nov 2018

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

Nov 2018 → ...

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

10. Jan 2023

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

15. Feb 2023

Surface and Interface Analysis (Journal)

Tougaard, S. M. (Peer reviewer)

20. Apr 2023

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2008

Surface Science (Journal)

Tougaard, S. M. (Editor)

1. Jan 2009

Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

2013 → ...

Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

Aug 2013

Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

2014 → ...

Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

29. Dec 2014

Surface Science (Journal)

Tougaard, S. M. (Peer reviewer)

Apr 2018

Surface Science Spectra (Journal)

Tougaard, S. M. (Editor)

20. May 1989 → ...

Surface Science Spectra (Journal)

Tougaard, S. M. (Peer reviewer)

18. Mar 2016

Surface Science Spectra (Journal)

Tougaard, S. M. (Peer reviewer)

16. Dec 2018

Surface Science Spectra (Journal)

Tougaard, S. M. (Peer reviewer)

22. Dec 2018

Surface Science Spectra (Journal)

Tougaard, S. M. (Peer reviewer)

25. Oct 2021

Surface Science Spectra (Journal)

Tougaard, S. M. (Peer reviewer)

17. May 2022

Talk at "12th Joint Vacuum Conference (JVC-12)" in Hungary: "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Tougaard, S. M. (Lecturer)

23. Sept 2008

Talk at Charles University in Prague: "Characterization of nano-structured materials with XPS-peak shape analysis"

Tougaard, S. M. (Lecturer)

11. Nov 2009

Talk at "European Conference on Surface and Interface Analysis": Applicability of REELS to characterize the electronic properties of surface nano-structures"

Tougaard, S. M. (Lecturer)

10. Sept 2007

Talk at: "European Conference on Surface and Interface Analysis": "Tomography on the nanoscale by XPS; A new approach to visual 3D-imaging"

Tougaard, S. M. (Lecturer)

11. Sept 2007

Talk at Helsinki University of Technology: "Characterization of chemical composition and electronic properties of nano-structures"

Tougaard, S. M. (Lecturer)

13. Aug 2007

Talk at "Mads Clausen Institut", Sønderborg Denmark: "Characterization of Morphology and Electronic Properties of Surface Nano-structures with XPS and REELS"

Tougaard, S. M. (Lecturer)

26. Feb 2009

Talk at Materials Science Center, Sevilla: "XPS Imaging of Nano-structures"

Tougaard, S. M. (Lecturer)

16. Mar 2010

Talk at "Surface Analysis 2009; 31st AVS-Symposium on Applied Surface Analysis", California USA: "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Tougaard, S. M. (Lecturer)

22. Apr 2009

Talk at Tampere University of Technology 2007: "Algorithm for Automatic XPS data analysis and applications to 3D XPS imaging"

Tougaard, S. M. (Lecturer)

10. Aug 2007

Talk at Universitaet Wuerzburg: "Nano-scale in-depth composition and electronic properties of nano-structured thin films determined with XPS and REELS"

Tougaard, S. M. (Lecturer)

23. Jun 2009

Talk at 2nd IEEE International Nanoelectronics Conference in Shanghai, China: "3-Dimensional XPS Imaging of Surface Nano-structures; A New Technique"

Tougaard, S. M. (Lecturer)

26. Mar 2008

Talk at "Pacific Northwest National Laboratory", Washington-State, USA: "3-Dimensional Nano-Structure Information from X-Ray Photo Electron Spectroscopy"

Tougaard, S. M. (Lecturer)

30. Apr 2009

Talk at "55th IUVSTA Workshop: Electron Transport Parameters; Applications in Surface Analysis": "Validity of Yubero-Tougaard theory to quantitatively determine the dielectric properties of surface nanofilms"

Tougaard, S. M. (Lecturer)

16. Sept 2008

The Centre of Physical Experiments

Tougaard, S. M. (Visiting researcher)

18. Aug 2010 → 22. Aug 2010

The Dielectric Function and its application in nano-structure characterization

Tougaard, S. M. (Lecturer)

3. Apr 2014

The Journal of Chemical Physics (Journal)

Tougaard, S. M. (Peer reviewer)

15. Feb 2011

Ukendt (External organisation)

Tougaard, S. M. (Participant)

19. Oct 2015 → 22. Oct 2015

University of Indonesia

Tougaard, S. M. (Visiting researcher)

6. Apr 2014 → 9. Apr 2014

University of Seville

Tougaard, S. M. (Visiting researcher)

14. Mar 2010 → 19. Mar 2010

University of Seville

Tougaard, S. M. (Visiting researcher)

26. Jan 2014 → 31. Jan 2014

University of Southern Denmark

Tougaard, S. M. (Visiting lecturer)

16. Apr 2013 → 19. Apr 2013

University of Southern Denmark

Tougaard, S. M. (Visiting lecturer)

18. Jul 2016 → 25. Jul 2016

University of Southern Denmark (External organisation)

Tougaard, S. M. (Chairman)

Jan 2014

Various (Journal)

Tougaard, S. M. (Editor)

1. Jan 2007

Visited "Applied Materials" - leader in Nanomanufacturing Technology solutions; Santa Clara, California, USA

Tougaard, S. M. (Supervisor)

20. Apr 2009

Visited "KLA-Tencor" - leading semiconductor equipment manufacturer; Santa Clara, California, USA

Tougaard, S. M. (Advisor)

21. Apr 2009

Workshop on QUASES-Tougaard XPS

Tougaard, S. M. (Guest lecturer)

19. Sept 2019

Workshop on XPS-QUASES analysis

Tougaard, S. M. (Guest lecturer)

28. Sept 2017

Writing Scientific Papers

Tougaard, S. M. (Lecturer)

1. Apr 2014